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**Information Disclosure
Statement By Applicant**

(Use Several Sheets if Necessary)

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UDL1P065
Applicant:
Parvin et al.
Filing Date
October 10, 2001

 Application No.
09/889,186
Group
Unassigned 2878

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
OG	A	5,750,991	05/12/98	Moyers et al.			
OG	B	5,155,365	10/13/92	Cann et al.			
	C						
	D						
	E						
	F						
	G						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
OG	H	62-91879	04/27/87	Japan				
OG	I	WO 00/42446	01/11/00	PCT				
	J							
	K							
	L							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
OG	M	"Standard Test Method for Nondestructive Assay of Special Nuclear Material in Low-Density Scrap and Waste by Segmented Passive Gamma-Ray Scanning," September 1996, American Society for Testing and Materials.
OG	N	"Standard Test Method for Nondestructive Assay of Special Nuclear Material in Low Density Scrap and Waste by Segmented Passive Gamma-Ray Scanning," November 1989, American Society for Testing and Materials.
OG	O	Parker et al., "Transmission Measurement Correction for Self-Attenuation in Gamma-Ray Assays of Special Nuclear Materials," 1976, Nuclear Materials Management.
Examiner	Date Considered	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.